

CMOS Test Systems

Testing the conversion efficiency of CMOS image sensors

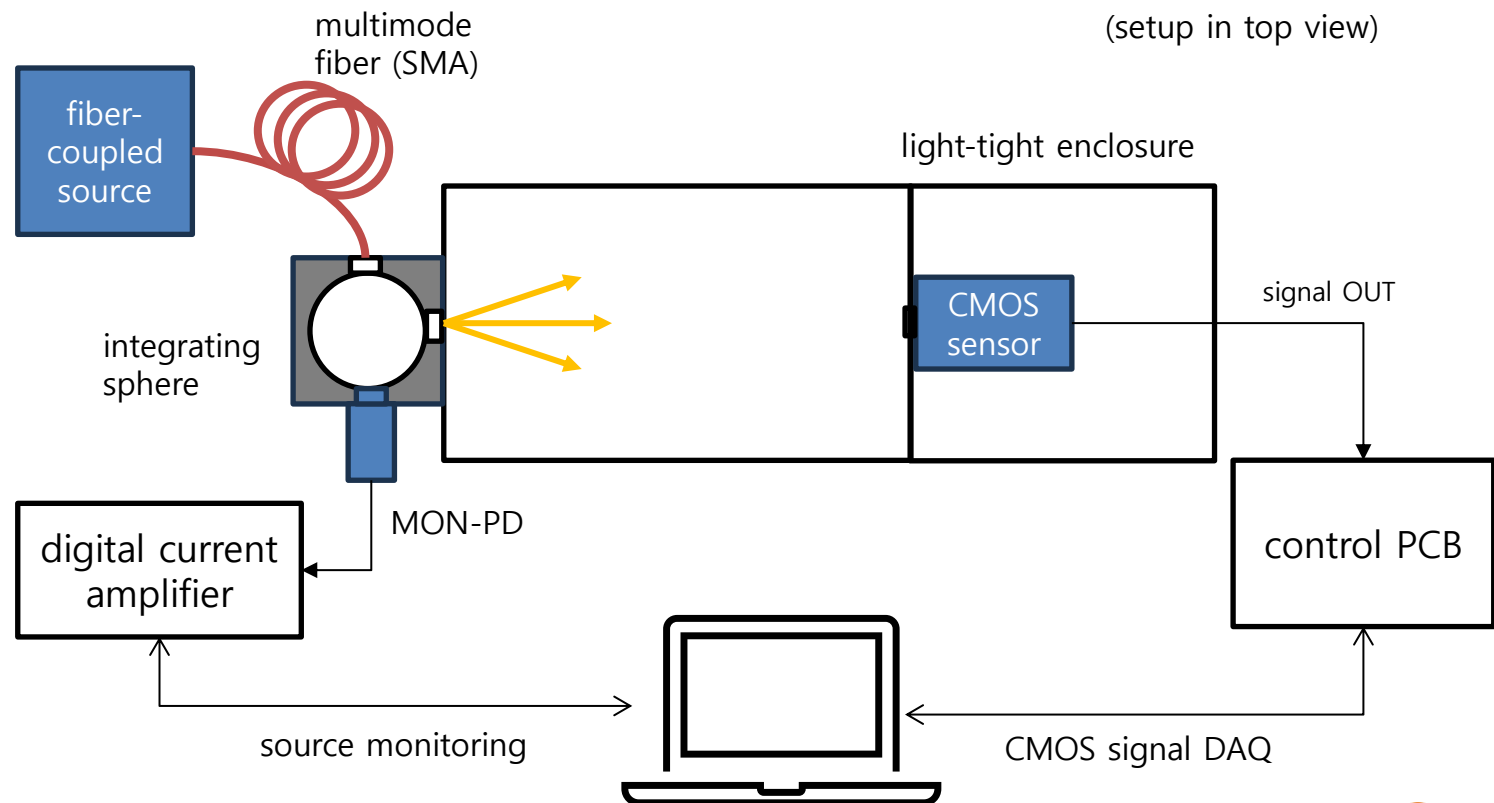
Model CTS

- CTS-QE (Quantum efficiency measurement with a spectrally tunable source)
- CTS-PTC (Photon Transfer Curve measurement with variable input level)

The System

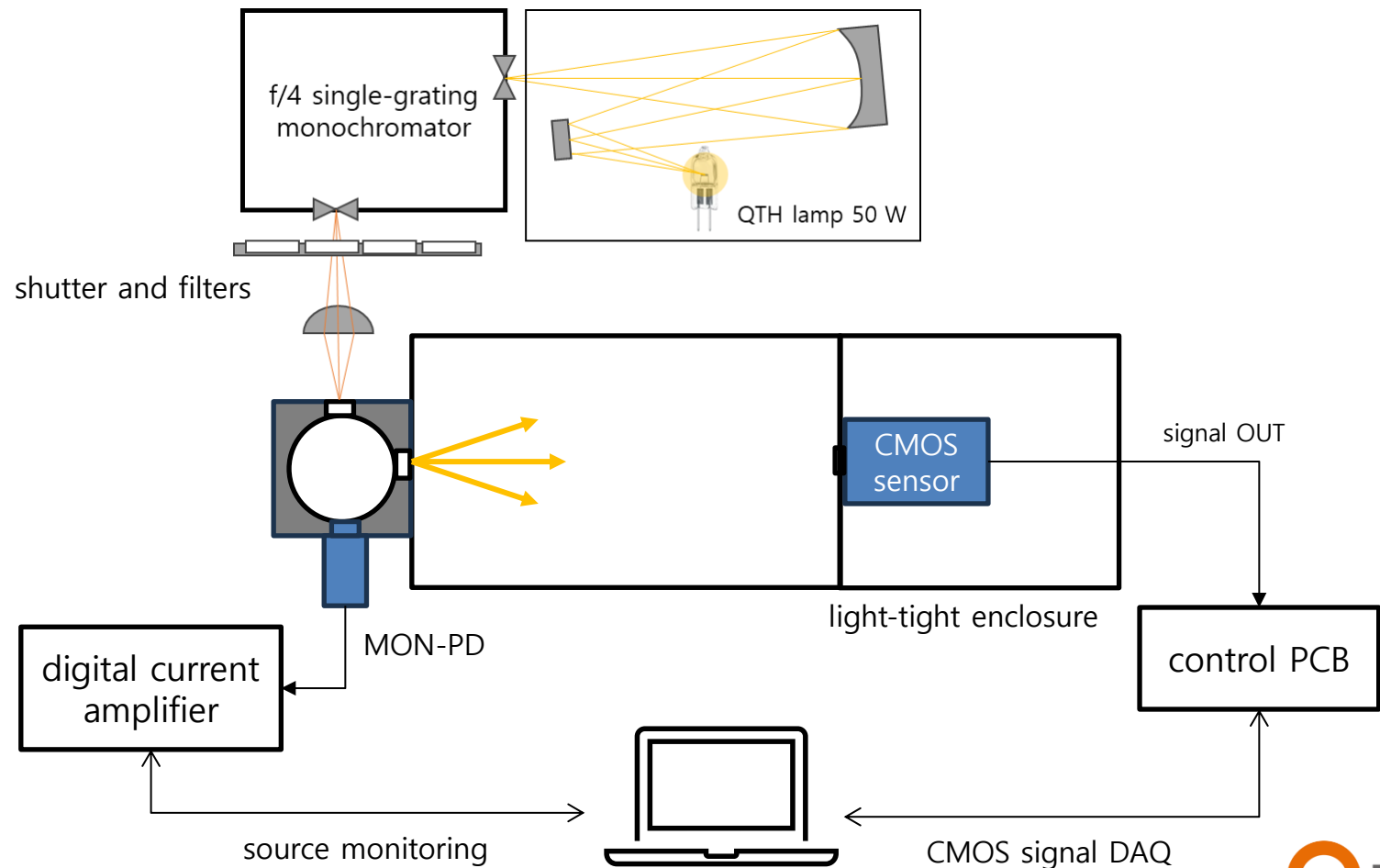
- CTS
- CTS-QE
- CTS-PTC

- Automated measurement of conversion efficiency of a CMOS image sensor at a selected source (monochromatic or white)
 - Uniform irradiation on the whole image sensor area $> 20 \text{ mm} \times 20 \text{ mm}$
 - Sensor input calibrated and monitored for radiance ($\text{W}/\text{m}^2\text{sr}$) or irradiance (W/m^2)
- Customized instrumentation solution including a software



Spectrally Tunable QE Measurement

- CTS combined with a spectrally tunable monochromatic light source
 - QE measured as a function of wavelength from 300 nm to 1000 nm
 - Sensor input calibrated and monitored for spectral irradiance (W/m^2)
- Fully automated measurement of QE with traceability to KRISS



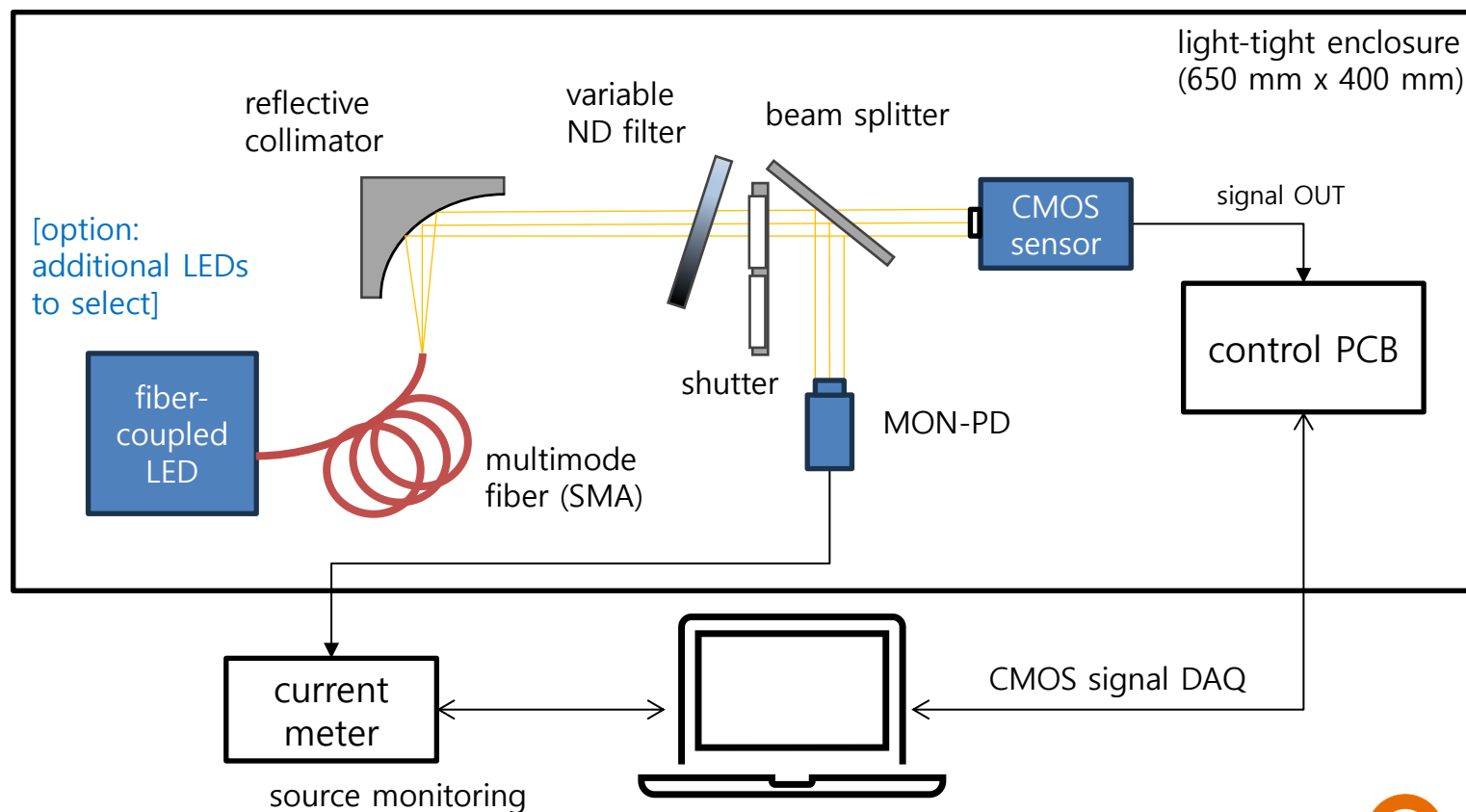
CTS

CTS-QE

CTS-PTC

PTC Measurement in High Dynamic Range

- High-dynamic range variation of light input
 - Collimated beam from the fiber-coupled LED source (beam diameter > 5 mm)
 - Computer-controlled variable ND filter for light input variation at up to 100 points
- Light input to the sensor monitored via a beam splitter
 - Calibrated for irradiance (W/m^2) and illuminance (lx) at the sensor position



• CTS

• CTS-QE

• CTS-PTC



QRAD for Quality in Optical Radiometry



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